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INTERNATIONAL STANDARD

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Electrostatics – **iTeh STANDARD PREVIEW** Part 2-3: Methods of test for determining the resistance and resistivity of solid materials used to avoid electrostatic charge accumulation

IEC 61340-2-3:2016

Électrostatique <u>https://standards.iteh.ai/catalog/standards/sist/d40defld-b0f7-4527-8fe4-</u> Partie 2-3: Méthodes d'essais pour la détermination de la résistance et de la résistivité des matériaux solides destinés à éviter les charges électrostatiques





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Electrostatics - iTeh STANDARD PREVIEW

Part 2-3: Methods of test for determining the resistance and resistivity of solid materials used to avoid electrostatic charge accumulation

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Électrostatique https://standards.iteh.ai/catalog/standards/sist/d40defld-b0f7-4527-8fe4-

Partie 2-3: Méthodes d'essais pour la détermination de la résistance et de la résistivité des matériaux solides destinés à éviter les charges électrostatiques

INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

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ELECTROSTATICS -

Part 2-3: Methods of test for determining the resistance and resistivity of solid materials used to avoid electrostatic charge accumulation

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International Standard IEC 61340-2-3 has been prepared by IEC technical committee 101: Electrostatics.

This second edition cancels and replaces the first edition published in 2000. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

 a) a distinction has been introduced between instrumentation used for laboratory evaluations, instrumentation used for acceptance testing and instrumentation used for compliance verification (periodic testing);

- b) an alternative electrode assembly is described, which can be used on non-planar products or when the dimensions of the product under test are too small to allow the larger electrode assembly to be used;
- c) the formulae for calculating surface and volume resistivity have been modified to correspond with common industry practice in the main areas of application for the IEC 61340 series.

The text of this standard is based on the following documents:

| CDV | Report on voting |
|-------------|------------------|
| 101/470/CDV | 101/494/RVC |

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 61340 series, published under the general title *Electrostatics*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be the specific publication of the specific publication will be the specific publication of the specific publication.

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INTRODUCTION

Measurements of resistances and related calculations of resistivities belong to the fundamental objectives of electrical measuring techniques along with measurements of voltage and current.

Resistivity is the electrical characteristic having the widest range, extending over some thirty orders of magnitude from the most conductive metal to almost perfect insulators.

The basis is Ohm's law and is valid for DC current and instantaneous values of AC current in electron conductors (metals, carbon, etc.). Values of resistance measurements using AC current can be influenced by capacitive/inductive reactance, depending on the frequency. Thus, existing national and international standards dealing with resistance measurements of solid materials normally require the application of DC current.

Most non-metal materials such as plastics are classified as polymers and ion conductors. The transport of charges can be dependent upon the applied electrical field strength during the measurement. Beside the measuring current, there exists a charging current that polarizes and/or electrostatically charges the material, indicated by an asymptotic decay of the measuring current with time and causing an apparent change in resistance. If this effect is observed, it will be advisable to repeat the measurement immediately after a definite electrification time has elapsed using the reverse polarity for the measuring current and averaging both obtained values.

iTeh STANDARD PREVIEW (standards.iteh.ai)

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ELECTROSTATICS –

Part 2-3: Methods of test for determining the resistance and resistivity of solid materials used to avoid electrostatic charge accumulation

1 Scope

This part of IEC 61340 describes test methods for the determination of the electrical resistance and resistivity of solid materials used to avoid electrostatic charge accumulation, in which the measured resistance is in the range $10^4 \Omega$ to $10^{12} \Omega$.

It takes account of existing IEC/ISO standards and other published information, and gives recommendations and guidelines on the appropriate method.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies. (standards.iteh.ai)

IEC 62631-3-1, Dielectric and resistive properties of solid insulating materials – Part 3-1: Determination of resistive properties (DC4 Methods) – Volume resistance and volume resistivity – General method ards.iteh.ai/catalog/standards/sist/d40defld-b0f7-4527-8fe4-3257f34aba7ffiec-61340-2-3-2016

IEC 62631-3-2, Dielectric and resistive properties of solid insulating materials – Part 3-2: Determination of resistive properties (DC Methods) – Surface resistance and surface resistivity

IEC 62631-3-3, Dielectric and resistive properties of solid insulating materials – Part 3-3: Determination of resistive properties (DC Methods) – Insulation resistance

ISO 1853, Conducting and dissipative rubbers, vulcanized or thermoplastic – Measurement of resistivity

ISO 2951, Rubber, vulcanized or thermoplastic – Determination of insulation resistance

ISO 3915, *Plastics – Measurement of resistivity of conductive plastics*

ISO 7619-1, *Rubber, vulcanized or thermoplastic – Determination of indentation hardness – Part 1: Durometer method (Shore hardness)*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply:

3.1

electrode

conductor of defined shape, size and configuration being in contact with the specimen to be measured

3.2

resistance

R

ratio of a DC voltage (V) applied between two points and the steady-state current (A) between the two points

- 8 -

Note 1 to entry: Resistance is expressed in ohms.

3.3

resistance to ground

Rq

resistance measured between an electrode placed on the surface of a test specimen and a local ground

Note 1 to entry: Resistance to ground is expressed in ohms.

3.4

resistance to groundable point

R_{gp}

resistance measured between an electrode placed on the surface of a test specimen and a groundable point fitted to the test specimen

Note 1 to entry: Resistance to groundable point is expressed in ohms.

3.5 **iTeh STANDARD PREVIEW** *R*_{pp} **(standards.iteh.ai)**

resistance measured between two electrodes placed a specified distance apart on the same surface of a test specimen
IEC 61340-2-3:2016

https://standards.iteh.ai/catalog/standards/sist/d40def1d-b0f7-4527-8fe4-Note 1 to entry: Point-to-point resistance_is_expressed in ohms. 225/15-4007//Jec-61340-2-3-2016

3.6

surface resistance

Rs

resistance measured between a central disc electrode and a surrounding concentric ring electrode placed on the surface of a test specimen

Note 1 to entry: Surface resistance is expressed in ohms.

3.7

surface resistivity

 ho_{s}

resistivity equivalent to the surface resistance of a square area, having the electrodes at two opposite sides

Note 1 to entry: The SI unit of surface resistivity (Ω) is sometimes referred to as Ω /sq (ohms per square), to distinguish resistivity values from resistance values. However, the use of Ω /sq is deprecated because it may imply a resistance per unit area, which is not correct.

3.8 volume resistance

 R_v

resistance measured between two electrodes placed on opposite surfaces of a test specimen

Note 1 to entry: Volume resistance is expressed in ohms.

3.9 volume resistivity

 ho_{v}

ratio of a DC field strength (V/m) and the steady-state current density (A/m²) within the material

-9-

Note 1 to entry: In practice, it is equivalent to the volume resistance of a cube with unit length, having the electrodes at two opposite surfaces.

Note 2 to entry: Volume resistivity is not an appropriate characteristic for materials that are electrically inhomogeneous.

Note 3 to entry: Volume resistivity is expressed in ohm meters.

4 Conditioning and test environment

The electrostatic behaviour of materials is influenced by environmental conditions, such as relative humidity and temperature.

For this reason, measurements shall be performed under controlled conditions. The selection of the appropriate conditions for testing shall be decided according to the type of material (product specification) and the intended application, based on the most severe conditions expected to occur during usage (e.g. lowest humidity and highest humidity).

Unless otherwise agreed, the atmosphere for conditioning and testing shall be (23 ± 2) °C and (12 ± 3) % relative humidity, and the conditioning time prior to testing shall be at least 24 h. (standards.iteh.ai)

If it is required to test that the measured resistance is not below a minimum limit, additional testing at high humidity is required. Unless otherwise agreed, the atmosphere for conditioning and testing at high humidity shall be (23 ± 2) °C and (60 ± 10) % relative humidity, and the conditioning time prior to testing shall be at least 24 h.

Specimens shall normally be conditioned and measured in the same climate, if not specified differently. However, preconditioning may be necessary in order to eliminate the effects of stress appearing after the moulding process of some plastic materials or as a drying treatment before the test procedure starts. Preconditioning is normally done in a different environment.

Adequate devices are a desiccator in an oven or a climate chamber preferably equipped with forced circulation and interchange of air.

5 Selection of test method

For planar materials, the following procedure shall be used to select the test method:

- a) if the range of electrical resistance of a material to be tested is known, then use the relevant clause (Clause 6, 7, 8 or 10) where appropriate standards are listed or methods described;
- b) for a material of initially unknown resistivity, start the measurements by using methods for conductive materials according to Clause 6.

If the measurement is not possible or the obtained result exceeds the given range for the application of the test method, it shall be regarded as being inadequate and the result shall not be taken into account. The measurement shall be repeated according to Clause 8 or Clause 10 for electrostatic dissipative materials. If the situation described above occurs again, the measurement shall be repeated according to Clause 7 for insulating materials.

For non-planar materials and for products with structures that are too small to allow the use of the electrode assemblies specified in 8.2, the method described in Clause 10 shall be used.

If the measurement result using the method described in Clause 10 is less than $10^4 \Omega$ or greater than $10^{12} \Omega$, and the shape or dimensions of the material under test do not allow measurements according to Clause 6 or Clause 7, the test result shall be reported as either "< $10^4 \Omega$ " or "> $10^{12} \Omega$ ".

6 Resistance measurements for solid conductive materials

The resistance of solid conductive materials (non-metals) shall be measured in accordance with ISO 3915 for plastics or ISO 1853 for rubbers. If the measured resistance is greater than or equal to $10^4 \Omega$, use the methods described in Clause 7, 8 or 10.

7 Resistance measurements for solid insulating materials

The resistance of solid insulating materials shall be measured in accordance with IEC 62631-3-1, IEC 62631-3-2 or IEC 62631-3-3 for plastics, or ISO 2951 for rubbers.

8 Resistance measurements for planar electrostatic dissipative materials (used to avoid electrostatic charge accumulation)

8.1 Instrumentation (standards.iteh.ai)

8.1.1 General

IEC 61340-2-3:2016

The instrumentation may consist of either a DCst power supply 2 and 4 an ammeter, or an integrated instrument (ohmmeter). National safety regulations shall be followed.

8.1.2 Instrumentation for laboratory evaluation

The output voltage under load shall be (100 \pm 5) V for measurements of 1 \times 10⁶ Ω and higher, and (10,0 \pm 0,5) V for less than 1 \times 10⁶ Ω .

If an ohmmeter is used, readings shall be possible at least from 1 \times 10³ Ω to 1 \times 10¹³ Ω , with an accuracy of ±10 %.

If a DC power supply and ammeter are used, readings shall be possible at least from 10 pA to 10 mA. The combined accuracy of the DC power supply and ammeter shall be ± 10 %.

8.1.3 Instrumentation for acceptance testing

Instrumentation for laboratory evaluation or instrumentation meeting the following requirements shall be used for acceptance testing.

The open circuit voltage shall be (100 ± 5) V for measurements of 1 × 10⁶ Ω and higher, and (10,0 ± 0,5) V for less than 1 × 10⁶ Ω .

If an ohmmeter is used, readings shall be possible at least from 1 \times 10³ Ω to 1 \times 10¹³ Ω , with an accuracy of ±20 %.

If a DC power supply and ammeter are used, readings shall be possible at least from 10 pA to 10 mA with an accuracy of ± 20 %.

In case of dispute, instrumentation for laboratory evaluations shall be used.

8.1.4 Instrumentation for compliance verification (periodic testing)

Instrumentation meeting the requirements for laboratory evaluations or acceptance testing, or instrumentation meeting the following requirements shall be used.

Compliance verification instrumentation shall be capable of making measurements one order of magnitude above and below the intended measurement range. The output voltage of compliance verification instrumentation may vary from laboratory evaluation or acceptance testing instrumentation, and may be rated under load or open circuit. Compliance verification instrumentation shall be checked against laboratory evaluation or acceptance testing instrumentation to ensure there is correlation between measurement results.

In case of dispute, instrumentation for acceptance testing or laboratory evaluation shall be used.

8.2 Electrode assemblies

8.2.1 General

The electrodes shall consist of a material that allows intimate contact with the specimen surface and introduces no appreciable error because of electrode resistance or contamination of the specimen. The electrode material shall be corrosion resistant under test conditions and shall not cause a chemical reaction with the material being tested.

The assemblies described in the subclauses below are recommended to be suitable, but other configurations complying with national or international standards may also be used, if appropriate. Especially for volume resistance measurements of electrostatic dissipative materials, it is important that applied probes of the guarded ring type have sufficient space between the centre (measuring) and ring (guard) contact electrode in order to minimize stray currents falsifying the readings. It is recommended, that the gap g shall be at least 10 mm. In cases of dispute, the assemblies described in this standard shall be applied.

8.2.2 Assembly for the measurement of surface resistance

The electrode assembly (probe 1) contains a central disc surrounded by a concentric ring made of conductive materials which make contact with the material under test (see Figure 1). The total mass of the electrode assembly shall be $(2,5 \pm 0,25)$ kg.

The contact surface material shall have a volume resistance of less than $10^3 \Omega$ when tested on a stainless, non-corrosive metal plate (not aluminium) as the counter electrode by applying (10,0 ± 0,5) V, and shall have a Shore A hardness of 50 to 70 when tested according to ISO 7619-1.

Insulating materials used in the electrode assembly shall have volume and/or surface resistance greater than 10^{13} Ω when tested according to IEC 62631-3-1 and/or IEC 62631-3-2 respectively.

The material under test shall be placed on an insulating support as described in 8.2.5.

Dimensions in millimetres



Figure 1 – Example of an assembly for the measurement of surface and volume resistance

8.2.3 Assembly for the measurement of volume resistance

The assembly consists of two electrodes placed on either side of the material under test (see Figure 4). The top electrode assembly (probe 1) shall be as described in 8.2.2 and shown in Figure 1.

The bottom electrode (probe 2) shall be a stainless, non-corrosive metal plate (not aluminium) sufficiently large to support the specimen under test. Probe 2 shall be equipped with a permanent connecting terminal (e.g. plug hole, riveted connector). Crocodile clips should not be used.

It should be placed either on an insulating support as described in 8.2.5 prior to test or be equipped with equivalent insulating feet.

8.2.4 Assembly for the measurement of resistance to ground/groundable point and point-to-point resistance

The assembly consists of one (resistance to ground/groundable point) or two (point-to-point resistance) electrodes (probe 3) containing a disk made of conductive material which makes contact with the material under test (see Figure 2). The total mass of the electrode assembly shall be $(2,5 \pm 0,25)$ kg.

The contact surface material shall be conductive enough that two probes placed on a metal surface (e.g. probe 2) have a point-to-point resistance of less than $10^3 \Omega$ when tested with $(10,0 \pm 0,5)$ V, and shall have a Shore A hardness of 50 to 70 when tested according to ISO 7619-1.

Insulating materials used in the electrode assembly shall have volume and/or surface resistance greater than $10^{13} \Omega$ when tested according to IEC 62631-3-1 and/or IEC 62631-3-2 respectively.

The material under test shall be placed on an insulating support as described in 8.2.5.

Dimensions in millimetres

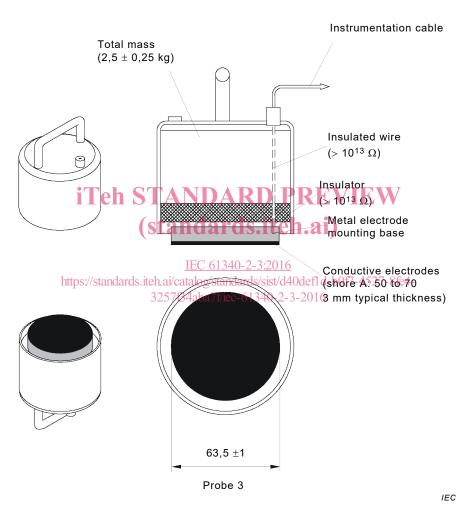


Figure 2 – Example of an assembly for the measurement of resistance to ground/groundable point and point-to-point resistance

8.2.5 Test support

The material shall be tested on a smooth flat support having a surface resistance greater than $1 \times 10^{13} \Omega$, measured according to IEC 62631-3-2. The size shall be at least 10 mm more in length and width compared to the size of the specimen under test. The minimum thickness shall be 1 mm.

8.3 Sample preparation and handling

Refer to applicable material specifications for sampling instructions. The specimens shall not be handled or marked in areas where measurements will be performed. If the areas where